- Driver Version of 'AS00
- High Capacitive-Drive Capability
- Package Options Include Plastic Small-Outline (D) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

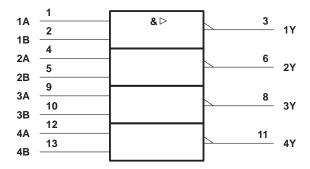
#### description

These devices contain four independent 2-input positive-NAND buffers/drivers. They perform the Boolean functions  $Y = \overline{A \bullet B}$  or  $Y = \overline{A} + \overline{B}$  in positive logic.

The SN54AS1000A is characterized for operation over the full military temperature range of  $-55^{\circ}$ C to 125°C. The SN74AS1000A is characterized for operation from 0°C to 70°C.

FUNCTION TABLE (each gate) INPUTS OUTPUT Α в Υ Н Н L L Н Х Х L Н

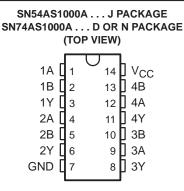
### logic symbol<sup>†</sup>



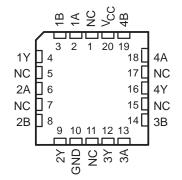
<sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for the D, J, and N packages.

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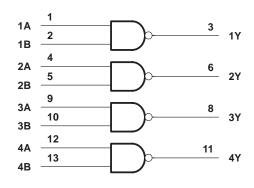


SN54AS1000A . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

#### logic diagram (positive logic)



PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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#### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)<sup>†</sup>

Supply voltage, V <sub>CC</sub>	
Input voltage, V <sub>1</sub>	
Operating free-air temperature range, T <sub>A</sub> : SN54AS1000A	-55°C to 125°C
SN74AS1000A	0°C to 70°C
Storage temperature range	-65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

#### recommended operating conditions<sup>‡</sup>

		SN54AS1000A			SN74AS1000A			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
VCC	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage	2			2			V
VIL	Low-level input voltage			0.8			0.8	V
ЮН	High-level output current			-40			-48	mA
IOL	Low-level output current			40			48	mA
TA	Operating free-air temperature	-55		125	0		70	°C

<sup>‡</sup>These high sink- or source-current devices are not recommended for use above 40 MHz.

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETER	TEST CONDITIONS		SN5	SN54AS1000A			SN74AS1000A			
PARAMETER			MIN	TYP§	MAX	MIN	TYP§	MAX	UNIT	
VIK	V <sub>CC</sub> = 4.5 V,	lı = -18 mA			-1.2			-1.2	V	
Vон	V <sub>CC</sub> = 4.5 V to 5.5 V,	$I_{OH} = -2 \text{ mA}$	V <sub>CC</sub> -2	2		V <sub>CC</sub> -2				
	V <sub>CC</sub> = 4.5 V	I <sub>OH</sub> = -3 mA	2.4	3.2		2.4	3.2		v	
		$I_{OH} = -40 \text{ mA}$	2							
		I <sub>OH</sub> = -48 mA				2				
Ve	V <sub>OL</sub> V <sub>CC</sub> = 4.5 V	I <sub>OL</sub> = 40 mA		0.25	0.5				v	
VOL		I <sub>OL</sub> = 48 mA					0.35	0.5		
Ц	V <sub>CC</sub> = 5.5 V,	V <sub>I</sub> = 7 V			0.1			0.1	mA	
Iн	V <sub>CC</sub> = 5.5 V,	V <sub>I</sub> = 2.7 V			20			20	μΑ	
١ <sub>IL</sub>	V <sub>CC</sub> = 5.5 V,	V <sub>I</sub> = 0.4 V			-0.5			-0.5	mA	
۱ <sub>0</sub> ۹	V <sub>CC</sub> = 5.5 V,	V <sub>O</sub> = 2.25 V	-30		-200	-50		-200	mA	
ІССН	V <sub>CC</sub> = 5.5 V,	$V_{I} = 0$		2.2	3.5		2.2	3.5	mA	
ICCL	V <sub>CC</sub> = 5.5 V,	V <sub>I</sub> = 4.5 V		12	19		12	19	mA	

§ All typical values are at V<sub>CC</sub> = 5 V,  $T_A = 25^{\circ}C$ .

The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, IOS.



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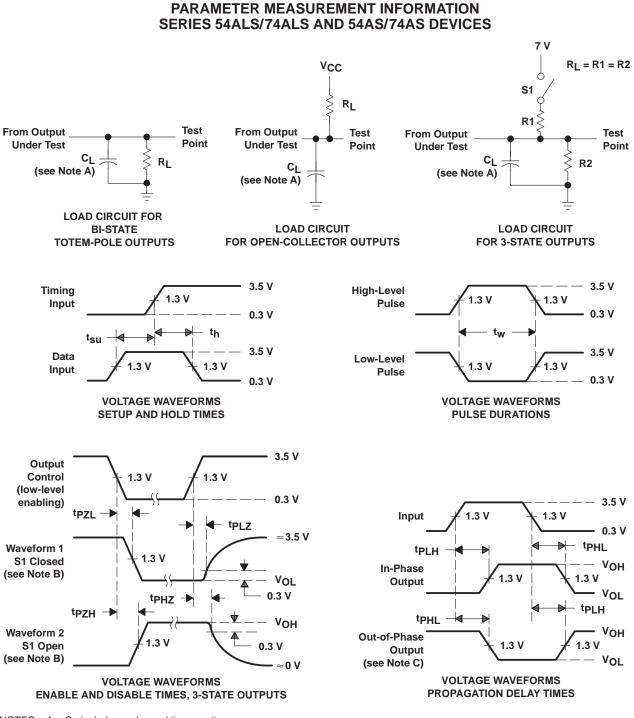
## switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	CL RL TA	$\label{eq:VCC} \begin{array}{c} V_{CC} = 4.5 \ V \ to \ 5.5 \ V, \\ C_L = 50 \ pF, \\ R_L = 500 \ \Omega, \\ T_A = MIN \ to \ MAX^{\dagger} \\ \hline \\ SN54AS1000A \ SN74AS1000A \\ \hline \\ MIN \ MAX \ MIN \ MAX \end{array}$			UNIT
tPLH	A or B		1	5	1	4	
<sup>t</sup> PHL		ľ	1	5	1	4	ns

<sup>†</sup> For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.



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NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
  C. When measuring propagation delay items of 3-state outputs, switch S1 is open.
- D. All input pulses have the following characteristics: PRR  $\leq$  1 MHz, t<sub>f</sub> = t<sub>f</sub> = 2 ns, duty cycle = 50%.
- E. The outputs are measured one at a time with one transition per measurement.
  - Figure 1. Load Circuits and Voltage Waveforms



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